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PATENT ABSTRACTS OF JAPAN

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(72) Inventor: FUJII HIROYUKI (74) Representative:

(71) Applicant: MATSUSHITA ELECTRONICS

(54) MANUFACTURE OF RESIN-MOLD SEMICONDUCTOR DEVICE **AND SEALING DEVICE** 

USED THEREFOR

(57) Abstract:

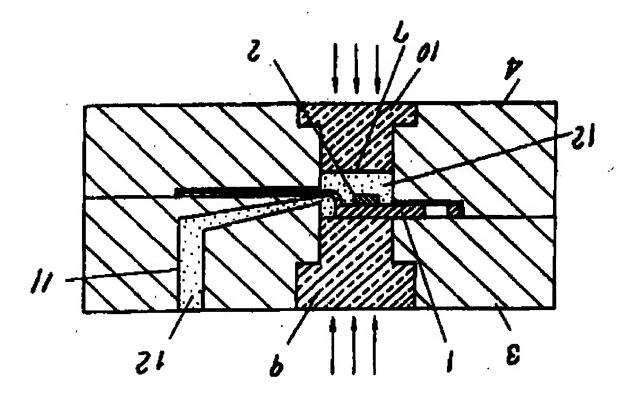
PURPOSE: To contrive the reduction resin of ultraviolet-curing type to be of the cost of resin sealing by using molding resin of ultraviolet-curing selectively cure only the molding type for sealing resin so as to poured in the cavity. https://www.delphion.com/cgi-bin/viewpat.cmd/JP59227131A2

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of the molding dies 3 and 4 consist of between the upper and lower molding supply bole 11. After that, the sealing wires has been completed is arranged CONSTITUTION: The built-up body through said layers 9 and 10 to reach cured. In this manufacturing method improvement of operation efficiency sealing molds is unnecessary so that and further connection by metal thin arrows. As the resin layers 9 and 10 type, the ultraviolet rays penetrates the cavity 7. Accordingly, only the subjected to curing reaction and is there is no waste of molding resin, supporting part 1 of the lead frame ultraviolet rays as indicated by the the resin of ultraviolet-transparent and heating of the resin and of the of a transistor in which a transistor element 2 is bonded to a substrate dies 3 and 4. Next, the ultravioletcuring resin 13 is poured into the and reduction of the cost of resin cavity 7 through a molding resin resin poured in the cavity 7 is molds are irradiated with the caling can be contrived.

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